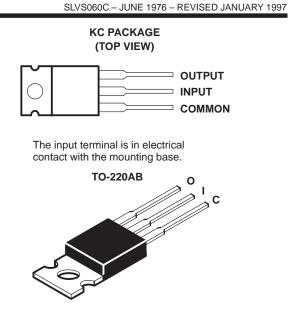
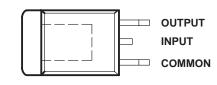
- **3-Terminal Regulators**
- Output Current Up to 500 mA
- **No External Components**
- **High Power Dissipation Capability**
- Internal Short-Circuit Current Limiting
- **Output Transistor Safe-Area Compensation**
- Direct Replacements for Fairchild µA79M00 Series

description

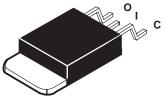
This series of fixed-negative-voltage monolithic integrated-circuit voltage regulators is designed to complement the µA78M00 series in a wide range of applications. These applications include on-card regulation for elimination of noise and distribution problems associated with single-point regulation. Each of these regulators can deliver up to 500 mA of output current. The internal current limiting and thermal shutdown features of these regulators make them essentially immune to overload. In addition to use as fixed-voltage regulators, these devices can be used with external components to obtain adjustable output voltages and currents and also as the power pass element in precision regulators.







The input terminal is in electrical contact with the mounting base.





µA79M12CKTP

µA79M15CKTP

µA79M20CKTP

µA79M24CKTP

-24 [†] The KTP package is also available in tape and reel.

-12

-15

-20



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

TA

0°C to 125°C



µA79M12CKC

μA79M15CKC

μA79M20CKC

µA79M24CKC

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μA79M12Y

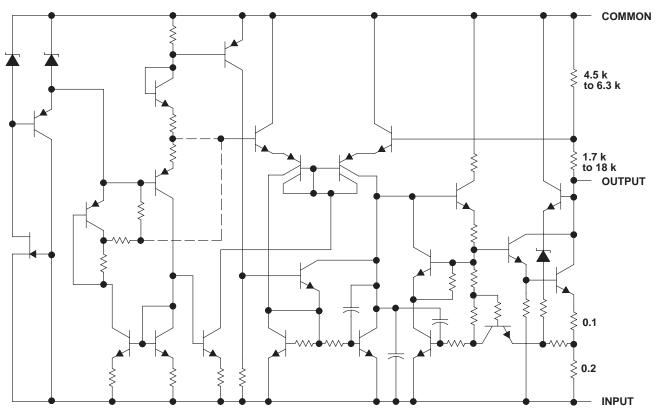
μA79M15Y

μA79M20Y

μA79M24Y

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schematic



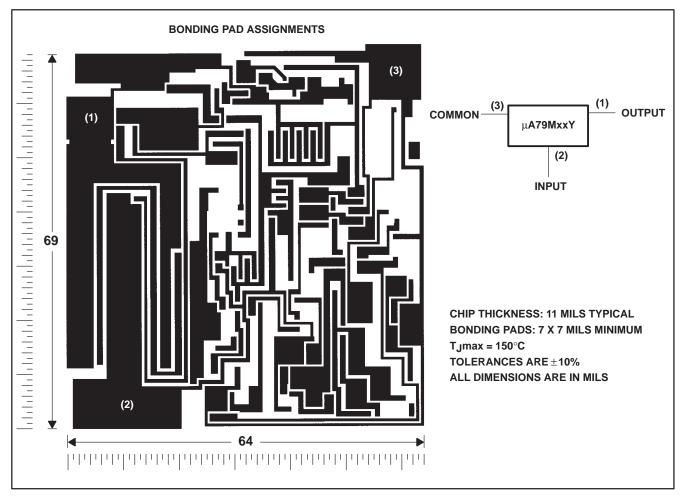
Resistor values shown are nominal and in Ω .



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μ A79MxxY chip information

This chip, when properly assembled, displays characteristics similar to the μ A79MxxC. Thermal compression or ultrasonic bonding can be used on the doped aluminum bonding pads. The chip can be mounted with conductive epoxy or a gold-silicon preform.





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absolute maximum ratings over operating temperature range (unless otherwise noted)[†]

	μ Α79ΜxxC	UNIT	
lanut voltogo	μΑ79Μ20, μΑ79Μ24	-40	V
Input voltage	All others	-35	v
Continuous total power dissipation (see Note 1)	-	See Dissipation Rating Tables	1 and 2
Operating free-air, T_A , case, T_C , or virtual junction, T_J , temperature range)	0 to 150	°C
Storage temperature range, T _{Stg}		-65 to 150	°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds		260	°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: To avoid exceeding the design maximum virtual junction temperature, these ratings should not be exceeded. Due to variations in individual device electrical characteristics and thermal resistance, the built-in thermal overload protection may be activated at power levels slightly above or below the rated dissipation.

DISSIPATION RATING TABLE 1-FREE-AIR TEMPERATURE

PACKAGE	T _A ≤ 25°C POWER RATING	DERATING FACTOR ABOVE T _A = 25°C	T _A = 70°C POWER RATING	T _A = 125°C POWER RATING
KC	2000 mW	16.0 mW/°C	1280 mW	400 mW
KTP	1800 mW	14.5 mW/°C	1147 mW	350 mW

DISSIPATION RATING TABLE 2-CASE TEMPERATURE

PACKAGE	T _C ≤ 120°C POWER RATING	DERATING FACTOR ABOVE T _C = 120°C	T _C = 125°C POWER RATING
KC	20000 mW	200.0 mW/°C	5000 mW
КТР	18000 mW	181.1 mW/°C	4365 mW

recommended operating conditions

		MIN	MAX	UNIT
	μA79M05C	-7	-25	
Input voltage, VI	μΑ79M06C	-8	-25	
	μΑ79M08C	-10.5	-25	
	μA79M12C	-14.5	30	V
	μA79M15C	-17.5	-30	
	μA79M20C	-23	-35	
	μA79M24C	-27	-38	
Output current, IO			500	mA
Operating virtual junction temperature, TJ			125	°C



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electrical characteristics at specified virtual junction temperature, $V_I = -10 V$, $I_O = 350 mA$, $T_J = 25^{\circ}C$ (unless otherwise noted)

		μ Α79Μ05C			
TEST CONDITIONS	ľ	MIN	TYP	MAX	UNIT
		-4.8	-5	-5.2	
$V_{I} = -7 V \text{ to } -25 V$, $I_{O} = 5 \text{ mA to } 350$ $T_{J} = 0^{\circ}\text{C} \text{ to } 125^{\circ}\text{C}$	mA,	-4.75		-5.25	V
$V_{I} = -7 V \text{ to } -25 V$			7	50	
$V_{I} = -8 V \text{ to} - 18 V$			3	30	mV
$V_{I} = -8 V \text{ to } -18 V$, $I_{O} = 100 \text{ mA}$, $T_{J} = 0^{\circ}\text{C} \text{ to } 125^{\circ}\text{C}$	c	50			dB
$I_0 = 300 \text{ mA}$		54	60		1
I _O = 5 mA to 500 mA			75	100	mV
IO = 5 mA to 350 mA			50		
$I_{O} = 5 \text{ mA},$ $T_{J} = 0^{\circ}\text{C to } 125^{\circ}\text{C}$	2		-0.4		mV/°C
f = 10 Hz to 100 kHz			125		μV
			1.1		V
			1	2	mA
$V_{I} = -8 V \text{ to} - 18 V$, $T_{J} = 0^{\circ} \text{C} \text{ to} 125^{\circ} \text{C}$	С (0.4	
$I_{O} = 5 \text{ mA to } 350 \text{ mA}, T_{J} = 0^{\circ}\text{C to } 125^{\circ}\text{C}$				0.4	mA
$V_{I} = -30 V$			140		mA
			0.65		A
	$T_{J} = 0^{\circ}C \text{ to } 125^{\circ}C$ $V_{I} = -7 \text{ V to } -25 \text{ V}$ $V_{I} = -8 \text{ V to } -18 \text{ V}$ $V_{I} = -8 \text{ V to } -18 \text{ V}, I_{O} = 100 \text{ mA}, \\T_{J} = 0^{\circ}C \text{ to } 125^{\circ}C$ $I_{O} = 300 \text{ mA}$ $I_{O} = 5 \text{ mA to } 500 \text{ mA}$ $I_{O} = 5 \text{ mA to } 350 \text{ mA}$ $I_{O} = 5 \text{ mA, } T_{J} = 0^{\circ}C \text{ to } 125^{\circ}C$ $f = 10 \text{ Hz to } 100 \text{ kHz}$ $V_{I} = -8 \text{ V to } -18 \text{ V}, T_{J} = 0^{\circ}C \text{ to } 125^{\circ}C$ $I_{O} = 5 \text{ mA to } 350 \text{ mA}, T_{J} = 0^{\circ}C \text{ to } 125^{\circ}C$	$\begin{array}{c} & & & & & \\ & &$	$\begin{tabular}{ c c c c } \hline TEST CONDITIONST & \hline MIN \\ \hline MIN \\ \hline & -4.8 \\ \hline V_I = -7 \ V \ to -25 \ V, \\ \hline T_J = 0^\circ C \ to \ 125^\circ C \\ \hline V_I = -7 \ V \ to \ -25 \ V \\ \hline V_I = -8 \ V \ to \ -18 \ V \\ \hline V_I = -8 \ V \ to \ -18 \ V, \\ \hline f = 120 \ Hz \\ \hline \hline IO = 100 \ mA, \\ \hline T_J = 0^\circ C \ to \ 125^\circ C \\ \hline IO = 300 \ mA \\ \hline IO = 5 \ mA \ to \ 350 \ mA \\ \hline IO = 5 \ mA \ to \ 350 \ mA \\ \hline IO = 5 \ mA \ to \ 350 \ mA \\ \hline IO = 5 \ mA \ to \ 350 \ mA \\ \hline IO = 5 \ mA \ to \ 350 \ mA \\ \hline \hline IO = 5 \ mA \ to \ 350 \ mA \\ \hline IO = 5 \ mA \ to \ 350 \ mA \ to \ 350 \ mA \\ \hline IO = 5 \ mA \ to \ 10 \ mA \ to \ 10 \ to \ 10 \ to \ 10 \ to \ 10 \ to$	$\begin{tabular}{ c c c c c } \hline TEST CONDITIONST & \hline MIN & TYP \\ \hline MIN & TYP \\ \hline -4.8 & -5 \\ \hline V_I = -7 \ V \ to -25 \ V, \\ T_J = 0 \ ^\circ C \ to \ 125 \ ^\circ C \\ \hline V_I = -7 \ V \ to \ -25 \ V \\ \hline V_I = -8 \ V \ to \ -18 \ V \\ \hline V_I = -8 \ V \ to \ -18 \ V \\ \hline T_J = 0 \ ^\circ C \ to \ 125 \ ^\circ C \\ \hline I_O = 100 \ mA, \\ T_J = 0 \ ^\circ C \ to \ 125 \ ^\circ C \\ \hline I_O = 300 \ mA \\ \hline S0 \\ \hline I_O = 5 \ mA \ to \ 500 \ mA \\ \hline I_O = 5 \ mA \ to \ 500 \ mA \\ \hline I_O = 5 \ mA \ to \ 500 \ mA \\ \hline I_O = 5 \ mA, \\ \hline T_J = 0 \ ^\circ C \ to \ 125 \ ^\circ C \\ \hline I_O = 5 \ mA \ to \ 350 \ mA \\ \hline I_J = 0 \ ^\circ C \ to \ 125 \ ^\circ C \\ \hline I_O = 5 \ mA \ to \ 350 \ mA \\ \hline I_J = 0 \ ^\circ C \ to \ 125 \ ^\circ C \\ \hline I_O = 5 \ mA \ to \ 350 \ mA \\ \hline I_J = 0 \ ^\circ C \ to \ 125 \ ^\circ C \\ \hline I_J = 10 \ Hz \ to \ 100 \ Hz \\ \hline I_J = 0 \ ^\circ C \ to \ 125 \ ^\circ C \\ \hline I_J = 10 \ Hz \ to \ 100 \ Hz \\ \hline I_J = 0 \ ^\circ C \ to \ 125 \ ^\circ C \\ \hline I_J = 5 \ mA \ to \ 350 \ mA, \\ \hline I_J = 0 \ ^\circ C \ to \ 125 \ ^\circ C \\ \hline I_J = 5 \ mA \ to \ 350 \ mA, \\ \hline I_J = 0 \ ^\circ C \ to \ 125 \ ^\circ C \\ \hline I_J = 5 \ mA \ to \ 350 \ mA, \\ \hline I_J = 0 \ ^\circ C \ to \ 125 \ ^\circ C \\ \hline I_J = 5 \ mA \ to \ 350 \ mA, \\ \hline I_J = 0 \ ^\circ C \ to \ 125 \ ^\circ C \\ \hline I_J = 5 \ mA \ to \ 350 \ mA, \\ \hline I_J = 0 \ ^\circ C \ to \ 125 \ ^\circ C \\ \hline I_J = 5 \ mA \ to \ 350 \ mA, \\ \hline I_J = 0 \ ^\circ C \ to \ 125 \ ^\circ C \\ \hline I_J = 5 \ ^\circ C \ to \ 125 \ ^\circ C \\ \hline I_J = 5 \ ^\circ C \ to \ 125 \ ^\circ C \\ \hline I_J = 5 \ ^\circ C \ to \ 125 \ ^\circ C \\ \hline I_J = 5 \ ^\circ C \ to \ 125 \ ^\circ C \\ \hline I_J = 5 \ ^\circ C \$	$\begin{tabular}{ c c c c c } \hline TEST CONDITIONST & \hline MIN & TYP & MAX \\ \hline MIN & TYP & MAX \\ \hline -4.8 & -5 & -5.2 \\ \hline V_I = -7 \ V \ to -25 \ V, \\ T_J = 0^\circ \ C \ to 125^\circ \ C & & & & & & & & & & & & & & & & & &$

[†] Pulse-testing techniques maintain T_J as close to T_A as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 2- μ F capacitor across the input and a 1- μ F capacitor across the output.

[‡] This specification applies only for dc power dissipation permitted by absolute maximum ratings.

electrical characteristics at specified virtual junction temperature, $V_I = -11 V$, $I_O = 350 mA$, $T_J = 25^{\circ}C$ (unless otherwise noted)

PARAMETER	TEAT OF	ONDITIONS [†]	μ	479M06	C	LINUT
PARAMETER	TEST CO	JNDITIONS	MIN	TYP	MAX	UNIT
			-5.75	-6	-6.25	
Output voltage‡	$V_{I} = -8 V \text{ to } -25 V,$ $T_{J} = 0^{\circ}C \text{ to } 125^{\circ}C$	$I_{O} = 5 \text{ mA to } 350 \text{ mA},$	-5.7		-6.3	V
Input voltage regulation	$V_{I} = -8 V \text{ to } -25 V$			7	60	
	$V_{I} = -9 V \text{ to} - 19 V$			3	40	mV
Ripple rejection	$V_{I} = -9 V \text{ to } -19 V$, f = 120 Hz	$I_O = 100 \text{ mA},$ $T_J = 0^{\circ}C \text{ to } 125^{\circ}C$	50			dB
	1 = 120 HZ	I _O = 300 mA	54	60		
	I _O = 5 mA to 500 mA	١		80	120	
Output voltage regulation	$I_{O} = 5 \text{ mA to } 350 \text{ mA}$	١		55		mV
Temperature coefficient of output voltage	IO = 5 mA,	$T_J = 0^{\circ}C$ to $125^{\circ}C$		-0.4		mV/°C
Output noise voltage	f = 10 Hz to 100 kHz			150		μV
Dropout voltage				1.1		V
Bias current				1	2	mA
	$V_{I} = -9 V \text{ to } -25 V,$	$T_J = 0^{\circ}C$ to $125^{\circ}C$			0.4	
Bias current change	$I_{O} = 5 \text{ mA to } 350 \text{ mA}$	$T_J = 0^\circ C$ to $125^\circ C$			0.4	mA
Short-circuit output current	V _I = -30 V			140		mA
Peak output current				0.65		А

[†] Pulse-testing techniques maintain T_J as close to T_A as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 2-μF capacitor across the input and a 1-μF capacitor across the output.



μ<mark>Α79Μ00 SERIES</mark> NEGATIVE-VOLTAGE REGULATORS

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electrical characteristics at specified virtual junction temperature, $V_I = -19 V$, $I_O = 350 mA$, $T_J = 25^{\circ}C$ (unless otherwise noted)

DADAMETED	TEAT OON	TEST CONDITIONS [†]		μ Α79Μ08C		
PARAMETER	TESTCON			TYP	MAX	UNIT
			-7.7	-8	-8.3	
Output voltage‡	$V_{I} = -10.5 V \text{ to } -25 V,$ $T_{J} = 0^{\circ}\text{C} \text{ to } 125^{\circ}\text{C}$	I_{O} = 5 mA to 350 mA,	-7.6		-8.4	V
Input voltage regulation	$V_{I} = -10.5 \text{ V to } -25 \text{ V}$			8	80	mV
	$V_{I} = -11 \text{ V to } -21 \text{ V}$			4	50	mv
Ripple rejection	$V_{I} = -11.5 V \text{ to } -21.5 V,$ f = 120 Hz	$I_{O} = 100 \text{ mA},$ $T_{J} = 0^{\circ}\text{C} \text{ to } 125^{\circ}\text{C}$	50			dB
	T = 120 HZ	I _O = 300 mA	54	59		
Output voltage regulation	IO = 5 mA to 500 mA	-		90	160	mV
Output voltage regulation	$I_{O} = 5 \text{ mA to } 350 \text{ mA}$			60		mv
Temperature coefficient of output voltage	I _O = 5 mA,	$T_J = 0^{\circ}C$ to $125^{\circ}C$		-0.6		mV/°C
Output noise voltage	f = 10 Hz to 100 kHz			200		μV
Dropout voltage	I _O = 5 mA			1.1		V
Bias current				1	2	mA
Diag surrent shares	$V_{I} = -10.5 \text{ V to } -25 \text{ V},$	T _J = 0°C to 125°C			0.4	
Bias current change	$I_{O} = 5 \text{ mA to } 350 \text{ mA},$	T _J = 0°C to 125°C			0.4	mA
Short-circuit output current	V _I = -30 V			140		mA
Peak output current				0.65		A

[†] Pulse-testing techniques maintain T_J as close to T_A as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 2-μF capacitor across the input and a 1-μF capacitor across the output.

[‡]This specification applies only for dc power dissipation permitted by absolute maximum ratings.

electrical characteristics at specified virtual junction temperature, $V_I = -19 V$, $I_O = 350 mA$, $T_J = 25^{\circ}C$ (unless otherwise noted)

DADAMETED	TEAT A	TEST CONDITIONS [†]		A79M12	2C	LINUT
PARAMETER	TESTC	TEST CONDITIONS			MAX	UNIT
			-11.5	-12	-12.5	
Output voltage [‡]	$V_I = -14.5 V \text{ to } -30$ $T_J = 0^{\circ}\text{C} \text{ to } 125^{\circ}\text{C}$	V, $I_{O} = 5 \text{ mA to } 350 \text{ mA}$,	-11.4		-12.6	V
	V _I = −14.5 V to −30	V		9	80	
Input voltage regulation	$V_{I} = -15 V \text{ to } -25 V$	1		5	50	mV
Ripple rejection	$V_{I} = -15V \text{ to } -25 \text{ V},$ f = 120 Hz	$I_O = 100 \text{ mA},$ $T_J = 0^{\circ}C \text{ to } 125^{\circ}C$	50			dB
	1 = 120 HZ	IO = 300 mA	54	60		1
	I _O = 5 mA to 500 m/	A		65	240	
Output voltage regulation	$I_{O} = 5 \text{ mA to } 350 \text{ m/}$	Α		45		mV
Temperature coefficient of output voltage	IO = 5 mA,	$T_J = 0^{\circ}C$ to $125^{\circ}C$		-0.8		mV/°C
Output noise voltage	f = 10 Hz to 100 kHz	2		300		μV
Dropout voltage				1.1		V
Bias current				1.5	3	mA
D'an anna daharan	V _I = −14.5 V to −30	V, $T_J = 0^{\circ}C$ to $125^{\circ}C$			0.4	
Bias current change	$I_{O} = 5 \text{ mA to } 350 \text{ m/}$	$I_{O} = 5 \text{ mA to } 350 \text{ mA}, T_{J} = 0^{\circ}\text{C to } 125^{\circ}\text{C}$				mA
Short-circuit output current	V _I = -30 V			140		mA
Peak output current				0.65		A

[†] Pulse-testing techniques maintain T_J as close to T_A as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 2-μF capacitor across the input and a 1-μF capacitor across the output.



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electrical characteristics at specified virtual junction temperature, $V_I = -23 V$, $I_O = 350 mA$, $T_J = 25^{\circ}C$ (unless otherwise noted)

	TEST CON		μA	A79M15	С	
PARAMETER	TESTCON	TEST CONDITIONS [†]			MAX	UNIT
			-14.4	-15	-15.6	
Output voltage‡	$V_{I} = -17.5 V \text{ to } -30 V,$ $T_{J} = 0^{\circ}\text{C} \text{ to } 125^{\circ}\text{C}$	$I_{O} = 5 \text{ mA to } 350 \text{ mA},$	-14.25		-15.75	V
Input voltage regulation	$V_{I} = -17.5 \text{ V to } -30 \text{ V}$			9	80	mV
	$V_{I} = -18 \text{ V to } -28 \text{ V}$			7	50	
Ripple rejection	$V_{I} = -18.5 V \text{ to } -28.5 V,$ f = 120 Hz	$I_{O} = 100 \text{ mA},$ $T_{J} = 0^{\circ}\text{C} \text{ to } 125^{\circ}\text{C}$	50			dB
	1 = 120 HZ	I _O = 300 mA	54	59		1
	$I_{O} = 5 \text{ mA to } 500 \text{ mA}$			65	240	mV
Output voltage regulation	$I_{O} = 5 \text{ mA to } 350 \text{ mA}$			45		
Temperature coefficient of output voltage	I _O = 5 mA,	$T_J = 0^{\circ}C$ to $125^{\circ}C$		-1		mV/°C
Output noise voltage	f = 10 Hz to 100 kHz			375		μV
Dropout voltage	IO = 5 mA			1.1		V
Bias current				1.5	3	mA
Diag ourrent change	$V_{I} = -17.5 V \text{ to } -30 V,$	$T_J = 0^{\circ}C$ to $125^{\circ}C$			0.4	mA
Bias current change	$I_{O} = 5 \text{ mA to } 350 \text{ mA},$	$T_J = 0^{\circ}C$ to $125^{\circ}C$			0.4	
Short-circuit output current	V _I = -30 V			140		mA
Peak output current				0.65		A

[†] Pulse-testing techniques maintain T_J as close to T_A as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 2-μF capacitor across the input and a 1-μF capacitor across the output.

[‡] This specification applies only for dc power dissipation permitted by absolute maximum ratings.

electrical characteristics at specified virtual junction temperature, $V_I = -29 V$, $I_O = 350 mA$, $T_J = 25^{\circ}C$ (unless otherwise noted)

DADAMETED	7507.00	TEST CONDITIONS [†]		479M20	С	LINUT
PARAMETER	TEST CO			TYP	MAX	UNIT
			-19.2	-20	-20.8	
Output voltage‡	$V_{I} = -23 V \text{ to } -35 V,$ $T_{J} = 0^{\circ}\text{C} \text{ to } 125^{\circ}\text{C}$	I_{O} = 5 mA to 350 mA,	-19		-21	V
Input voltage regulation	V _I = -23 V to -35 V			12	80	
	$V_{I} = -24 V \text{ to } -34 V$			10	70	mV
Ripple rejection	$V_{I} = -24 V \text{ to } -34 V,$ f = 120 Hz	$I_O = 100 \text{ mA},$ $T_J = 0^{\circ}C \text{ to } 125^{\circ}C$	50			dB
	1 = 120 HZ	IO = 300 mA	54	58		
	I _O = 5 mA to 500 mA			75	300	
Output voltage regulation	I _O = 5 mA to 350 mA			50		mV
Temperature coefficient of output voltage	IO = 5 mA,	$T_J = 0^{\circ}C$ to $125^{\circ}C$		-1		mV/°C
Output noise voltage	f = 10 Hz to 100 kHz			500		μV
Dropout voltage				1.1		V
Bias current				1.5	3.5	mA
Diag autreat change	$V_{I} = -23 V \text{ to } -35 V,$	$T_J = 0^{\circ}C$ to $125^{\circ}C$			0.4	A
Bias current change	I _O = 5 mA to 350 mA	$I_{O} = 5 \text{ mA to } 350 \text{ mA}, T_{J} = 0^{\circ}\text{C to } 125^{\circ}\text{C}$			0.4	mA
Short-circuit output current	V _I = -30 V			140		mA
Peak output current				0.65		Α

[†] Pulse-testing techniques maintain T_J as close to T_A as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 2-μF capacitor across the input and a 1-μF capacitor across the output.



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electrical characteristics at specified virtual junction temperature, $V_I = -33 V$, $I_O = 350 mA$, $T_J = 25^{\circ}C$ (unless otherwise noted)

DADAMETER	TEOTO	TEST CONDITIONS [†]		A79M24	С	
PARAMETER	IESICO			TYP	MAX	UNIT
			-23	-24	-25	
Output voltage‡	$V_{I} = -27 V \text{ to } -38 V,$ $T_{J} = 0^{\circ}\text{C} \text{ to } 125^{\circ}\text{C}$	I_{O} = 5 mA to 350 mA,	-22.8		-25.2	V
	$V_{I} = -27 V \text{ to } -38 V$			12	80	mV
Input voltage regulation	$V_{I} = -28 \text{ V to } -38 \text{ V}$			12	70	mv
Ripple rejection	$V_{I} = -28 V \text{ to } -38 V$, f = 120 Hz	I _O = 100 mA, T _J = 0°C to 125°C	50			dB
	f = 120 Hz	I _O = 300 mA	54	58		1
	I _O = 5 mA to 500 mA			75	300	
Output voltage regulation	$I_{O} = 5 \text{ mA to } 350 \text{ mA}$			50		mV
Temperature coefficient of output voltage	I _O = 5 mA,	$T_J = 0^{\circ}C$ to $125^{\circ}C$		-1		mV/°C
Output noise voltage	f = 10 Hz to 100 kHz			600		μV
Dropout voltage				1.1		V
Bias current				1.5	3.5	mA
Diag surrent shares	$V_{I} = -27 \text{ V to } -38 \text{ V},$	$T_J = 0^{\circ}C$ to $125^{\circ}C$			0.4	
Bias current change	$I_{O} = 5 \text{ mA to } 350 \text{ mA}$	$I_{O} = 5 \text{ mA to } 350 \text{ mA}, T_{J} = 0^{\circ}\text{C to } 125^{\circ}\text{C}$			0.4	mA
Short-circuit output current	V _I = -30 V			140		mA
Peak output current				0.65		А

[†] Pulse-testing techniques maintain T_J as close to T_A as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 2-μF capacitor across the input and a 1-μF capacitor across the output.



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electrical characteristics at specified virtual junction temperature, $V_I = -10 V$, $I_O = 350 mA$, $T_J = 25^{\circ}C$ (unless otherwise noted)

DADAMETED	TEST CONDITIONS [†]	μ	LINUT		
PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Output voltage [‡]			-5		V
Input voltage regulation	$V_{I} = -7 V \text{ to } -25 V$		7		
	$V_{I} = -8 V \text{ to } -18 V$		3		mV
Ripple rejection	$V_{I} = -8 V \text{ to} - 18 V$, $I_{O} = 300 \text{ mA}$, $f = 120 \text{ Hz}$		60		dB
	$I_{O} = 5 \text{ mA to } 500 \text{ mA}$		75		
Output voltage regulation	I _O = 5 mA to 350 mA		50		mV
Temperature coefficient of output voltage	$I_{O} = 5 \text{ mA}$		-0.4		mV/°C
Output noise voltage	f = 10 Hz to 100 kHz		125		μV
Dropout voltage			1.1		V
Bias current			1		mA
Short-circuit output current	$V_{I} = -30 V$		140		mA
Peak output current			0.65		A

⁺ Pulse-testing techniques maintain T_J as close to T_A as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 2-μF capacitor across the input and a 1-μF capacitor across the output.

[‡] This specification applies only for dc power dissipation permitted by absolute maximum ratings.

electrical characteristics at specified virtual junction temperature, $V_I = -11 V$, $I_O = 350 mA$, $T_J = 25^{\circ}C$ (unless otherwise noted)

PARAMETER	TEST CONDITIONS [†]	μ Α79Μ06	Y	LINUT
	TEST CONDITIONS	MIN TYP	MAX	UNIT
Output voltage [‡]		-6		V
Input voltage regulation	$V_{I} = -8 V \text{ to } -25 V$	7		mV
	$V_{I} = -9 V \text{ to } -19 V$	3		mv
Ripple rejection	$V_{I} = -9 V \text{ to} - 19 V$, $I_{O} = 300 \text{ mA}$, $f = 120 \text{ Hz}$	60		dB
Output voltage regulation	$I_{O} = 5 \text{ mA to } 500 \text{ mA}$	80		mV
	$I_{O} = 5 \text{ mA to } 350 \text{ mA}$	55		IIIV
Temperature coefficient of output voltage	$I_{O} = 5 \text{ mA}$	-0.4		mV/°C
Output noise voltage	f = 10 Hz to 100 kHz	150		μV
Dropout voltage		1.1		V
Bias current		1		mA
Short-circuit output current	$V_{I} = -30 V$	140		mA
Peak output current		0.65		А

[†] Pulse-testing techniques maintain T_J as close to T_A as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 2-μF capacitor across the input and a 1-μF capacitor across the output.



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electrical characteristics at specified virtual junction temperature, $V_I = -19 V$, $I_O = 350 mA$, $T_J = 25^{\circ}C$ (unless otherwise noted)

PARAMETER		μ Α79Μ08Υ			.
	TEST CONDITIONS [†]	MIN	TYP	MAX	UNIT
Output voltage [‡]			-8		V
Input voltage regulation	$V_{I} = -10.5 V \text{ to } -25 V$		8		
	$V_{I} = -11 V \text{ to } -21 V$		4		mV
Ripple rejection	$V_{I} = -11.5 \text{ V to } -21.5 \text{ V}, I_{O} = 300 \text{ mA}, f = 120 \text{ Hz}$		59		dB
Output voltage regulation	IO = 5 mA to 500 mA		90		
	IO = 5 mA to 350 mA		60		mV
Temperature coefficient of output voltage	I _O = 5 mA		-0.6		mV/°C
Output noise voltage	f = 10 Hz to 100 kHz		200		μV
Dropout voltage	IO = 5 mA		1.1		V
Bias current			1		mA
Short-circuit output current	$V_{I} = -30 V$		140		mA
Peak output current			0.65		A

[†] Pulse-testing techniques maintain T_J as close to T_A as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 2-μF capacitor across the input and a 1-μF capacitor across the output.

[‡] This specification applies only for dc power dissipation permitted by absolute maximum ratings.

electrical characteristics at specified virtual junction temperature, $V_I = -19 V$, $I_O = 350 mA$, $T_J = 25^{\circ}C$ (unless otherwise noted)

PARAMETER	TEST CONDITIONS [†]	μ Α79Μ12Υ			LINUT
	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Output voltage [‡]			-12		V
Input voltage regulation	$V_{I} = -14.5 V \text{ to } -30 V$		9		mV
nput voltage regulation	$V_{I} = -15 V \text{ to } -25 V$		5		mv
Ripple rejection	$V_{I} = -15V \text{ to } -25 \text{ V}, I_{O} = 300 \text{ mA}, f = 120 \text{ Hz}$		60		dB
	I _O = 5 mA to 500 mA		65		mV
Output voltage regulation	I _O = 5 mA to 350 mA		45		mv
Temperature coefficient of output voltage	$I_{O} = 5 \text{ mA}$		-0.8		mV/°C
Output noise voltage	f = 10 Hz to 100 kHz		300		μV
Dropout voltage			1.1		V
Bias current			1.5		mA
Short-circuit output current	$V_{I} = -30 V$		140		mA
Peak output current			0.65		А

[†] Pulse-testing techniques maintain T_J as close to T_A as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 2-μF capacitor across the input and a 1-μF capacitor across the output.



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electrical characteristics at specified virtual junction temperature, $V_I = -23 V$, $I_O = 350 mA$, $T_J = 25^{\circ}C$ (unless otherwise noted)

PARAMETER	TEST CONDITIONS [†]	μ Α79Μ15Υ			
	TEST CONDITIONST	MIN 1	ΓΥΡ Ι	MAX	UNIT
Output voltage [‡]			-15		V
	$V_{I} = -17.5 V \text{ to } -30 V$		9		
Input voltage regulation	$V_{I} = -18 V \text{ to } -28 V$		7		mV
Ripple rejection	$V_{I} = -18.5 \text{ V to } -28.5 \text{ V}, I_{O} = 300 \text{ mA}, f = 120 \text{ Hz}$		59		dB
Output voltage regulation	$I_{O} = 5 \text{ mA to } 500 \text{ mA}$		65		
	I _O = 5 mA to 350 mA		45		mV
Temperature coefficient of output voltage	$I_{O} = 5 \text{ mA}$		-1		mV/°C
Output noise voltage	f = 10 Hz to 100 kHz		375		μV
Dropout voltage	$I_{O} = 5 \text{ mA}$		1.1		V
Bias current			1.5		mA
Short-circuit output current	$V_{I} = -30 V$		140		mA
Peak output current			0.65		A

⁺ Pulse-testing techniques maintain T_J as close to T_A as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 2-μF capacitor across the input and a 1-μF capacitor across the output.

[‡]This specification applies only for dc power dissipation permitted by absolute maximum ratings.

electrical characteristics at specified virtual junction temperature, $V_I = -29 V$, $I_O = 350 mA$, $T_J = 25^{\circ}C$ (unless otherwise noted)

PARAMETER	TEST CONDITIONS [†]	μ Α79Μ20Υ			LINUT
	TEST CONDITIONS	MIN T	ΥP	MAX	UNIT
Output voltage [‡]			-20		V
Input voltage regulation	$V_{I} = -23 V \text{ to } -35 V$		12		mV
	$V_{I} = -24 V \text{ to } -34 V$		10		
Ripple rejection	$V_{I} = -24 V \text{ to} - 34 V$, $I_{O} = 300 \text{ mA}$, $f = 120 \text{ Hz}$		58		dB
Output voltage regulation	I _O = 5 mA to 500 mA		75		mV
	I _O = 5 mA to 350 mA		50		mv
Temperature coefficient of output voltage	IO = 5 mA		-1		mV/°C
Output noise voltage	f = 10 Hz to 100 kHz		500		μV
Dropout voltage			1.1		V
Bias current			1.5		mA
Short-circuit output current	$V_{I} = -30 V$		140		mA
Peak output current			0.65		A

[†] Pulse-testing techniques maintain T_J as close to T_A as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 2-μF capacitor across the input and a 1-μF capacitor across the output.



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electrical characteristics at specified virtual junction temperature, $V_I = -33 V$, $I_O = 350 mA$, $T_J = 25^{\circ}C$ (unless otherwise noted)

PARAMETER	TEST CONDITIONS [†]	μ Α79Μ24Υ			T
		MIN	TYP	MAX	UNIT
Output voltage [‡]			-24		V
Input voltage regulation	$V_{I} = -27 V \text{ to } -38 V$		12		
	$V_{I} = -28 V \text{ to } -38 V$		12		mV
Ripple rejection	$V_{I} = -28 V \text{ to } -38 V$, $I_{O} = 300 \text{ mA}$, $f = 120 \text{ Hz}$		58		dB
Output voltage regulation	I _O = 5 mA to 500 mA		75		
	I _O = 5 mA to 350 mA		50		mV
Temperature coefficient of output voltage	$I_{O} = 5 \text{ mA},$ $T_{J} = 0^{\circ}\text{C} \text{ to } 125^{\circ}\text{C}$		-1		mV/°C
Output noise voltage	f = 10 Hz to 100 kHz		600		μV
Dropout voltage			1.1		V
Bias current			1.5		mA
Short-circuit output current	$V_{I} = -30 V$		140		mA
Peak output current			0.65		Α

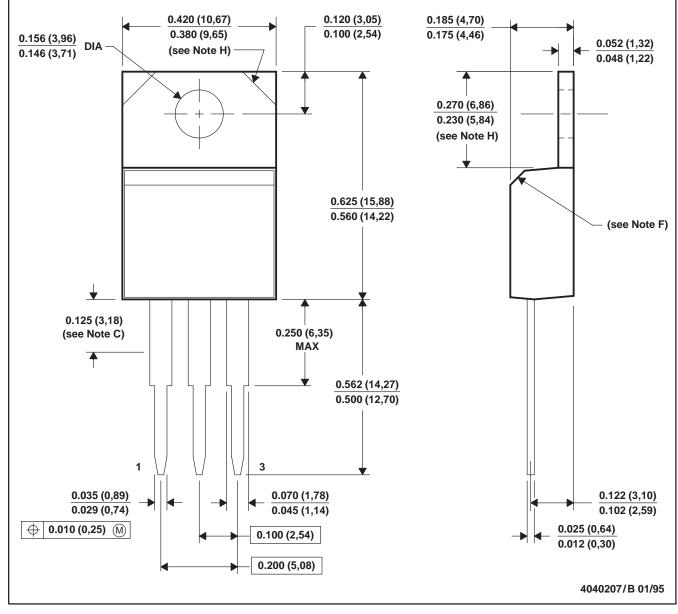
[†] Pulse-testing techniques maintain T_J as close to T_A as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 2-μF capacitor across the input and a 1-μF capacitor across the output.



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MECHANICAL INFORMATION

PLASTIC FLANGE-MOUNT PACKAGE



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- C. Lead dimensions are not controlled within this area.
- D. All lead dimensions apply before solder dip.
- E. The center lead is in electrical contact with the mounting tab.
- F. The chamfer is optional.

KC (R-PSFM-T3)

- G. Falls within JEDEC TO-220AB
- H. Tab contour optional within these dimensions

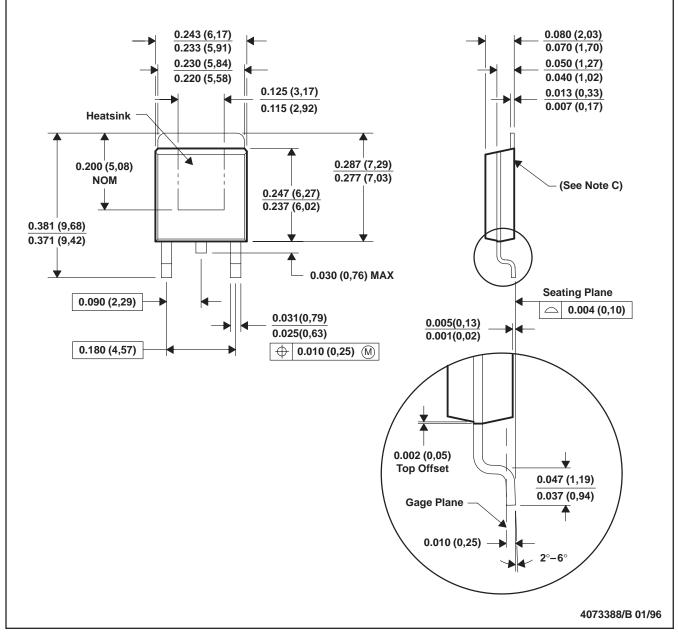


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MECHANICAL INFORMATION

KTP (R-PSFM-T3)

PLASTIC FLANGE-MOUNT PACKAGE



- NOTES: A. All linear dimensions are in inches (millimeters).
 - B. This drawing is subject to change without notice. C. The heatsink area is approximately 28K sq mils.



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